

April 2000

# FQB16N15 / FQI16N15

## 150V N-Channel MOSFET

## **General Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifire, high efficiency switching for DC/DC converters, and DC motor control, uninterrupted power supply.

#### **Features**

- 16.4A, 150V,  $R_{DS(on)}$  = 0.16 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 23 nC)
- Low Crss (typical 30 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating



# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQB16N15 / FQI16N15	Units	
V <sub>DSS</sub>	Drain-Source Voltage		150	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		16.4	Α	
	- Continuous (T <sub>C</sub> = 100°C)		11.6	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	65.6	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	230	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	16.4	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	10.8	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		3.75	W	
	Power Dissipation (T <sub>C</sub> = 25°C)		108	W	
	- Derate above 25°C		0.72	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C	
Tı	Maximum lead temperature for soldering pur	poses,	300	°C	
'L	1/8" from case for 5 seconds		300		

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.39	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	i	Min	Тур	Max	Units
Off Cha	aracteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		150			V
$\Delta BV_{DSS}$	Breakdown Voltage Temperature	I <sub>D</sub> = 250 μA, Referenced	to 25°C		0.17		V/°C
$/$ $\Delta T_{J}$	Coefficient		10 23 C		0.17		V/ C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 150 V, V <sub>GS</sub> = 0 V				1	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 120 V, T <sub>C</sub> = 150°C				10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V		-		100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -25 V, V <sub>DS</sub> = 0 V		I		-100	nA
On Cha	aracteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8.2 A			0.123	0.16	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 8.2 A	(Note 4)		9.5		S
C <sub>iss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz			700 145	910 190 40	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance				30	40	pF
	ing Characteristics				T		1
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 75 V, I <sub>D</sub> = 16.4 A,		-	11	30	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		-	115	240	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		(Note 4, 5)		50	110	ns
t <sub>f</sub>	Turn-Off Fall Time		. ,	-	80	170	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 120 V, I <sub>D</sub> = 16.4 A,	ı		23	30	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V	AL . 4.5\		4.5		nC
Q <sub>gd</sub>	Gate-Drain Charge		(Note 4, 5)		11		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings	5				
I <sub>S</sub>	Maximum Continuous Drain-Source Did					16.4	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	orward Current				65.6	Α
	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 16.4 \text{ A}$				1.5	V
$V_{SD}$	Brain Course Blode I of Ward Voltage						
V <sub>SD</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 16.4 A,		-	85		ns

- $\label{eq:Notes:1} \begin{tabular}{ll} \textbf{Notes:} \\ 1. & \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature} \\ 2. & \textbf{L} = 1.43mH, \textbf{I}_{AS} = 16.4A, \textbf{V}_{DD} = 25\text{V}, \textbf{R}_{G} = 25\,\Omega, \textbf{Starting} \quad \textbf{T}_{J} = 25^{\circ}\textbf{C} \\ 3. & \textbf{I}_{SD} \leq 16.4A, \textbf{di/dt} \leq 300A\mu\text{s}, \textbf{V}_{DD} \leq \textbf{BV}_{DSS}, \textbf{Starting} \quad \textbf{T}_{J} = 25^{\circ}\textbf{C} \\ 4. & \textbf{Pulse Test: Pulse width} \leq 300\mu\text{s}, \textbf{Duty cycle} \leq 2\% \\ 5. & \textbf{Essentially independent of operating temperature} \\ \end{tabular}$

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# **Typical Characteristics**

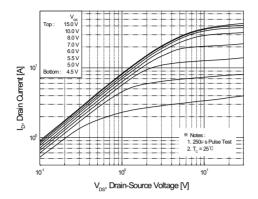


Figure 1. On-Region Characteristics

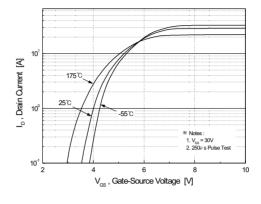


Figure 2. Transfer Characteristics

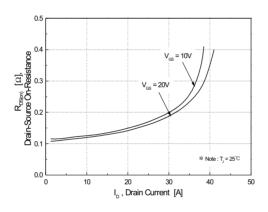


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

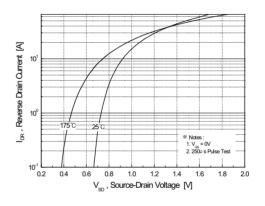


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

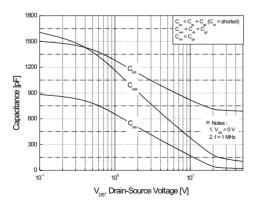


Figure 5. Capacitance Characteristics

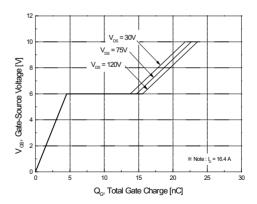
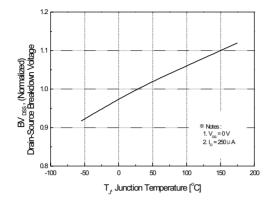


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)



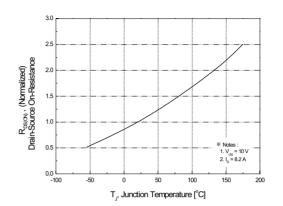
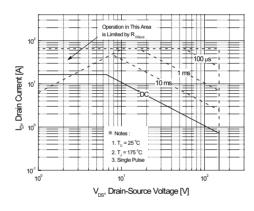


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



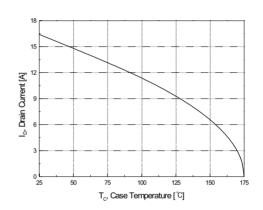


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

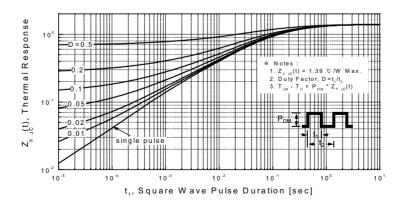
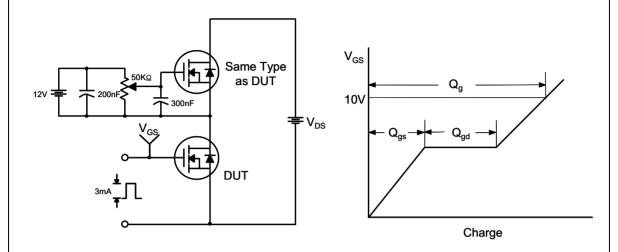


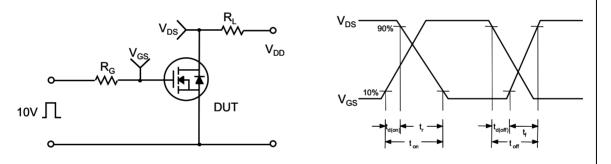
Figure 11. Transient Thermal Response Curve

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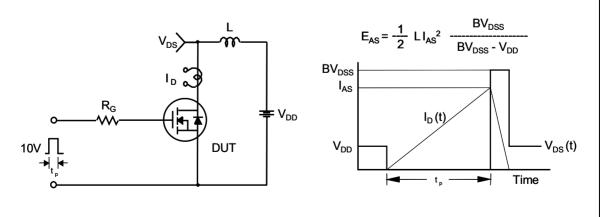
## **Gate Charge Test Circuit & Waveform**



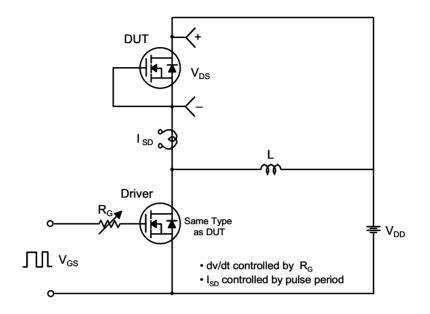
## **Resistive Switching Test Circuit & Waveforms**

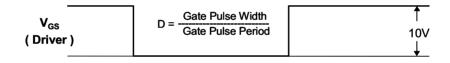


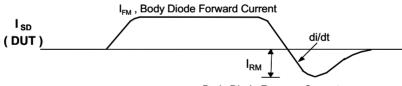
## **Unclamped Inductive Switching Test Circuit & Waveforms**



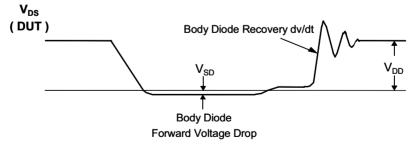
## Peak Diode Recovery dv/dt Test Circuit & Waveforms



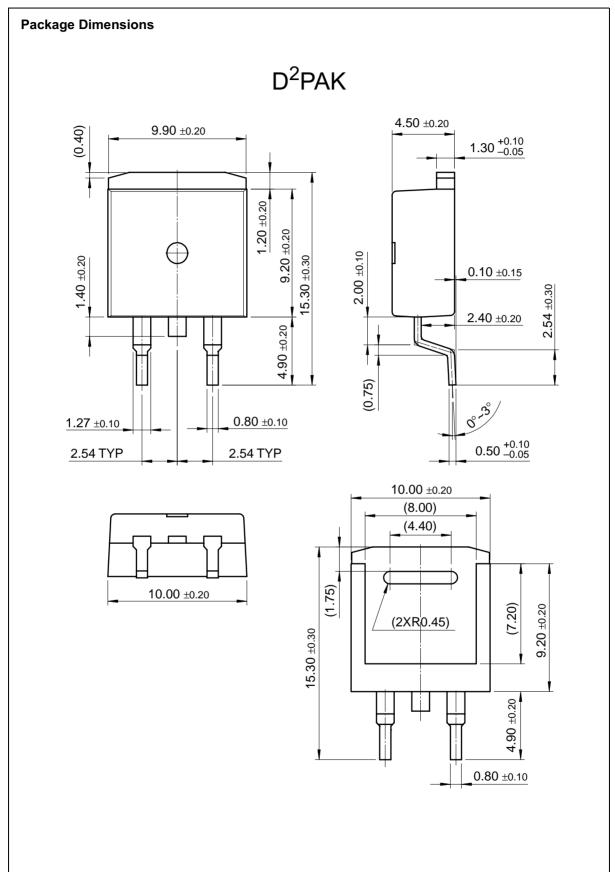


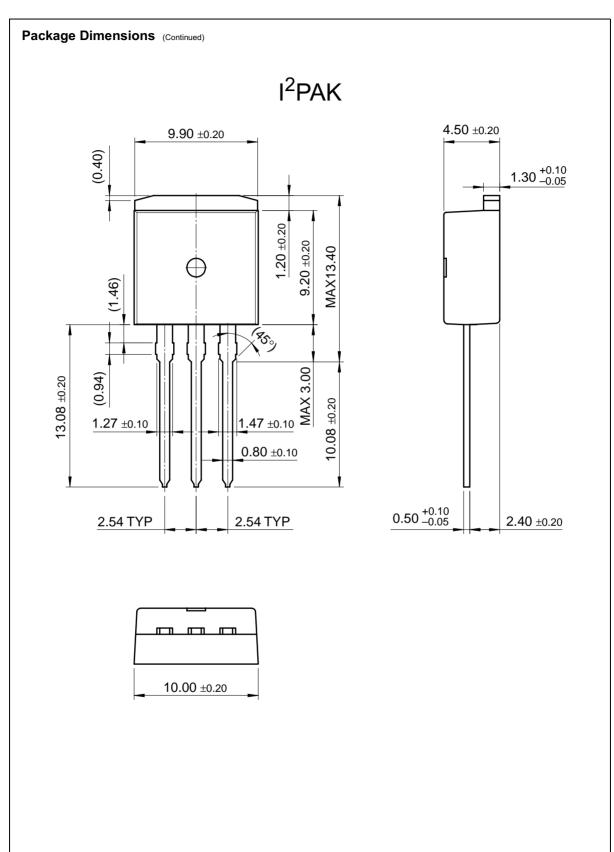


Body Diode Reverse Current



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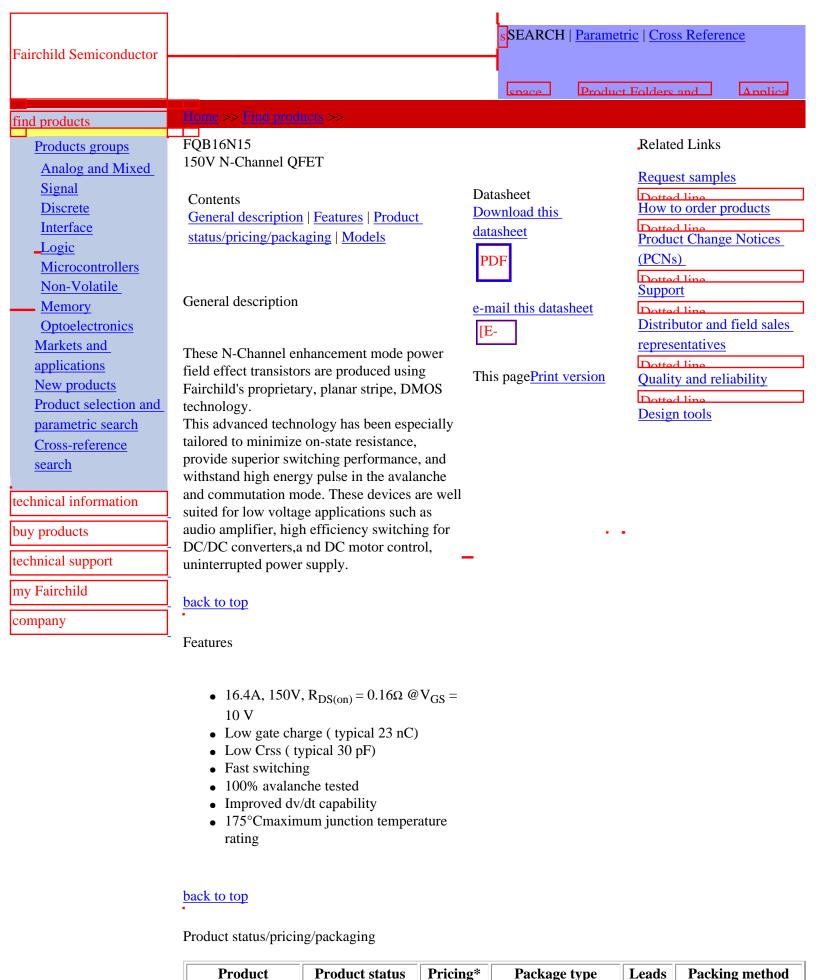
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back to top

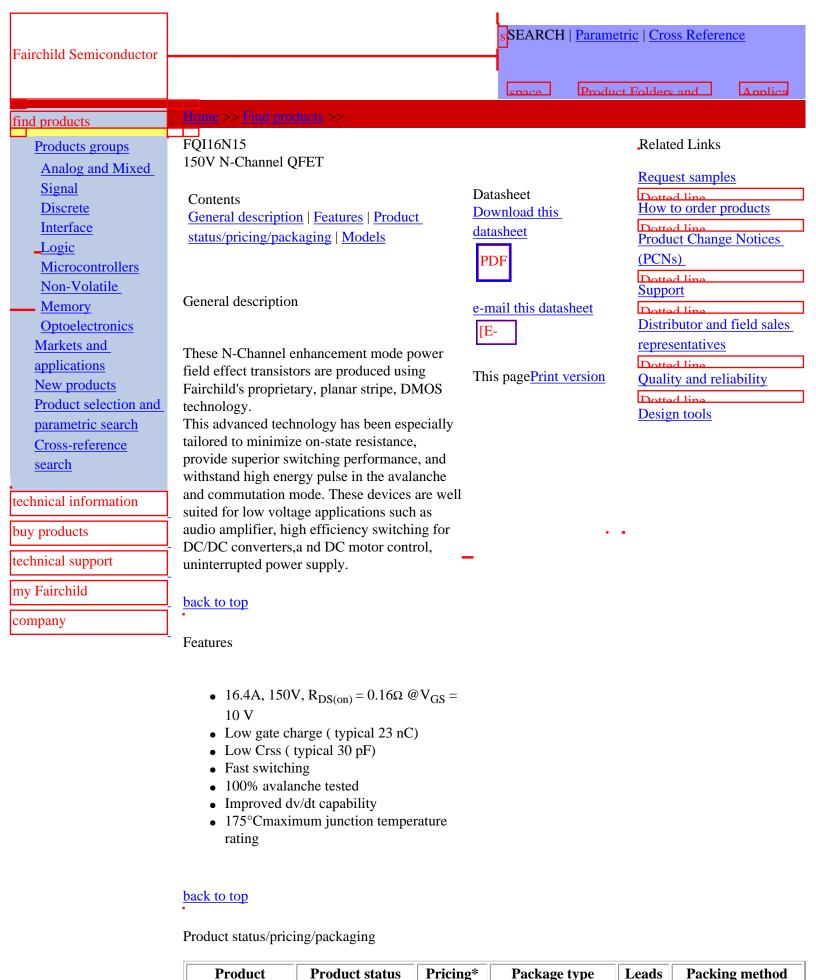
Models

Package & leads Condition		Temperature range	Software version	<b>Revision date</b>			
PSPICE							
TO-263(D2PAK)-2	Electrical/Thermal	-55°C to 175°C	9	Oct 21, 2000			

back to top

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# back to top

Models

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PSPICE				
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# back to top

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